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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/791,646	CHEN ET AL.	
Examiner	Art Unit	
Edward M. Johnson	1754	:

	SEARCHED		
Class	Subclass	Date	Examiner
502	151	3/17/2006	EJ
	170	1	1
	344		
	207		
	339		
560	243		
	245		
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
1			

SEARCH (INCLUDING SEAR		) .
	DATE	EXMR
Inventor name search	3/17/2006	EJ
EAST search in file		
09/454,316 consulted		
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